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|-----------------------------------|---------------------------------------|--|---------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 10/798,720 | | Applicant(s)/Patent Under Reexamination KRUMBEIN ET AL. | |
| | Examiner John M. Parker | | Art Unit 2823 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------------|----------------|
| * | A | US-2002/0137292 | 09-2002 | Hossain et al. | 438/289 |
| * | B | US-2004/0222461 | 11-2004 | Peyre-Lavigne et al. | 257/333 |
| * | C | US-6,833,585 | 12-2004 | Kim et al. | 257/343 |
| * | D | US-2002/0151124 | 10-2002 | Kim et al. | 438/197 |
| * | E | US-6,242,787 | 06-2001 | Nakayama et al. | 257/493 |
| * | F | US-5,705,842 | 01-1998 | Kitamura et al. | 257/362 |
| * | G | US-6,326,656 | 12-2001 | Tihanyi, Jenoe | 257/288 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

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